

RoHS Compliant Product  
A suffix of "-C" specifies halogen & lead-free

## DESCRIPTION

The SPRD8503-C is the highest performance trench N-Ch and P-Ch MOSFETs with extreme high cell density, which provide excellent  $R_{DS(ON)}$  and gate charge for most of the synchronous buck converter applications.

The SPRD8503-C meet the RoHS and Green Product requirement with full function reliability approved.

## FEATURES

- Advanced High Cell Density Trench Technology
- Super Low Gate Charge
- Green Device Available

## MARKING



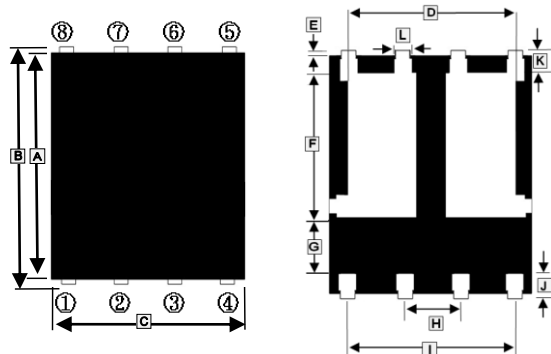
## PACKAGE INFORMATION

Package	MPQ	Leader Size
DFN5x6-8D	3K	13 inch

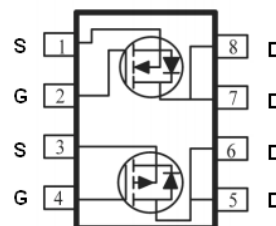
## ORDER INFORMATION

Part Number	Type
SPRD8503-C	Lead (Pb)-free and Halogen-free

## DFN5x6-8D



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.7	5.8	H	1.27 BSC.	
B	5.9	6.1	I	3.61	3.96
C	4.8	5	J	0.51	0.71
D	3.61	3.96	K	0.41	0.61
E	0.06	0.20	L	0.33	0.51
F	3.38	3.78	M	0.2	0.3
G	1.1	-	N	0.9	1.1



## ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ratings		Unit	
		N-Ch	P-Ch		
Drain-Source Voltage	$V_{DS}$	30	-30	V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 25$	V	
Continuous Drain Current, @ $V_{GS}=10V$ <sup>1</sup>	$I_D$	$T_C=25^\circ C$	36	-33	A
		$T_C=100^\circ C$	23	-21	
		$T_A=25^\circ C$	11	-10	
Pulsed Drain Current <sup>3</sup>	$I_{DM}$	64	-60	A	
Total Power Dissipation	$P_D$	$T_C=25^\circ C$	35.7		W
		$T_A=25^\circ C$	$t \leq 10s, 3.57$		
Operating Junction & Storage Temperature Range	$T_J, T_{STG}$	-55~150		$^\circ C$	
Thermal Data					
Thermal Resistance Junction-Ambient <sup>1</sup>	$R_{\theta JA}$	$t \leq 10s, 35$		$^\circ C/W$	
		Steady State, 62.5			
Thermal Resistance Junction-Ambient <sup>2</sup>		110			
Thermal Resistance Junction-Case <sup>1</sup>	$R_{\theta JC}$	3.5			

**N-CHANNEL ELECTRICAL CHARACTERISTICS** (T<sub>J</sub>=25°C unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions	
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	-	-	V	V <sub>GS</sub> =0, I <sub>D</sub> =250μA	
Gate Threshold Voltage	V <sub>GS(th)</sub>	1	-	2.5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	
Forward Transfer Conductance	g <sub>fs</sub>	-	34	-	S	V <sub>DS</sub> =5V, I <sub>D</sub> =30A	
Gate-Source Leakage Current	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> = ±20V	
Drain-Source Leakage Current	I <sub>DSS</sub>	T <sub>J</sub> =25°C	-	-	1	μA	V <sub>DS</sub> =24V, V <sub>GS</sub> =0
		T <sub>J</sub> =55°C	-	-	5		
Static Drain-Source On-Resistance <sup>4</sup>	R <sub>DS(ON)</sub>	-	9	12	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =12A	
		-	14	18		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A	
Total Gate Charge	Q <sub>g</sub>	-	9.8	-	nC	I <sub>D</sub> =12A V <sub>DS</sub> =15V V <sub>GS</sub> =4.5V	
Gate-Source Charge	Q <sub>gs</sub>	-	4.2	-			
Gate-Drain Charge	Q <sub>gd</sub>	-	3.6	-			
Turn-on Delay Time	T <sub>d(on)</sub>	-	4	-	nS	V <sub>DD</sub> =15V V <sub>GS</sub> =10V I <sub>D</sub> =12A R <sub>G</sub> =3.3Ω	
Rise Time	T <sub>r</sub>	-	8	-			
Turn-off Delay Time	T <sub>d(off)</sub>	-	31	-			
Fall Time	T <sub>f</sub>	-	4	-			
Input Capacitance	C <sub>iss</sub>	-	940	-	pF	V <sub>GS</sub> =0 V <sub>DS</sub> =15V f=1MHz	
Output Capacitance	C <sub>oss</sub>	-	131	-			
Reverse Transfer Capacitance	C <sub>rss</sub>	-	109	-			
<b>Source-Drain Diode</b>							
Forward on Voltage <sup>4</sup>	V <sub>SD</sub>	-	-	1.2	V	I <sub>S</sub> =1A, V <sub>GS</sub> =0, T <sub>J</sub> =25°C	
Continuous Source Current <sup>1</sup>	I <sub>S</sub>	-	-	36	A		
Pulsed Source Current <sup>3</sup>	I <sub>SM</sub>	-	-	64			
Reverse Recovery Time	T <sub>rr</sub>	-	8.5	-	nS	I <sub>F</sub> =30A, dI/dt=100A/μs, T <sub>J</sub> =25°C	
Reverse Recovery Charge	Q <sub>rr</sub>	-	2.2	-	nC		

Notes:

1. Surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2oz copper.
2. When mounted on Min. copper pad.
3. Pulse width limited by maximum junction temperature, pulse width ≤ 300μs, duty cycle ≤ 2%.
4. The data tested by pulsed, pulse width ≤ 300μs, duty cycle ≤ 2%.

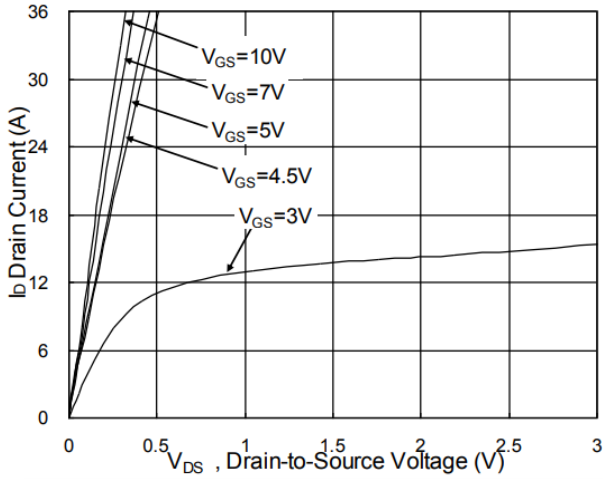
**P-CHANNEL ELECTRICAL CHARACTERISTICS** (T<sub>J</sub>=25°C unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions	
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-30	-	-	V	V <sub>GS</sub> =0, I <sub>D</sub> = -250μA	
Gate Threshold Voltage	V <sub>GS(th)</sub>	-1	-	-2.5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = -250μA	
Forward Transfer Conductance	g <sub>fs</sub>	-	30	-	S	V <sub>DS</sub> = -5V, I <sub>D</sub> = -30A	
Gate-Source Leakage Current	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> = ±20V	
Drain-Source Leakage Current	I <sub>DSS</sub>	T <sub>J</sub> =25°C	-	-	-1	μA	V <sub>DS</sub> = -24V, V <sub>GS</sub> =0
		T <sub>J</sub> =55°C	-	-	-5		
Static Drain-Source On-Resistance <sup>4</sup>	R <sub>DS(ON)</sub>	-	10	16	mΩ	V <sub>GS</sub> = -10V, I <sub>D</sub> = -12A	
		-	15	24		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -10A	
Total Gate Charge	Q <sub>g</sub>	-	22	-	nC	I <sub>D</sub> = -12A V <sub>DS</sub> = -15V V <sub>GS</sub> = -4.5V	
Gate-Source Charge	Q <sub>gs</sub>	-	8.7	-			
Gate-Drain Change	Q <sub>gd</sub>	-	7.2	-			
Turn-on Delay Time	T <sub>d(on)</sub>	-	8	-	nS	V <sub>DD</sub> = -15V V <sub>GS</sub> = -10V I <sub>D</sub> = -12A R <sub>G</sub> =3.3Ω	
Rise Time	T <sub>r</sub>	-	73.7	-			
Turn-off Delay Time	T <sub>d(off)</sub>	-	61.8	-			
Fall Time	T <sub>f</sub>	-	24.4	-			
Input Capacitance	C <sub>iss</sub>	-	2215	-	pF	V <sub>GS</sub> =0 V <sub>DS</sub> = -15V f=1MHz	
Output Capacitance	C <sub>oss</sub>	-	310	-			
Reverse Transfer Capacitance	C <sub>rss</sub>	-	237	-			
<b>Source-Drain Diode</b>							
Forward on Voltage <sup>4</sup>	V <sub>SD</sub>	-	-	-1.2	V	I <sub>S</sub> = -1A, V <sub>GS</sub> =0, T <sub>J</sub> =25°C	
Continuous Source Current <sup>1</sup>	I <sub>S</sub>	-	-	-33	A		
Pulsed Source Current <sup>3</sup>	I <sub>SM</sub>	-	-	-60			
Reverse Recovery Time	T <sub>rr</sub>	-	19	-	nS	I <sub>F</sub> = -15A, dI/dt=100A/μs, T <sub>J</sub> =25°C	
Reverse Recovery Charge	Q <sub>rr</sub>	-	9	-	nC		

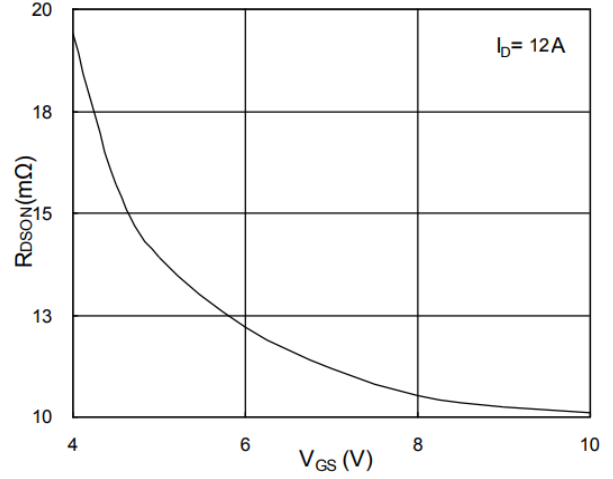
Notes:

1. Surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2oz copper.
2. When mounted on Min. copper pad.
3. Pulse width limited by maximum junction temperature, pulse width ≤ 300μs, duty cycle ≤ 2%.
4. The data tested by pulsed, pulse width ≤ 300μs, duty cycle ≤ 2%.

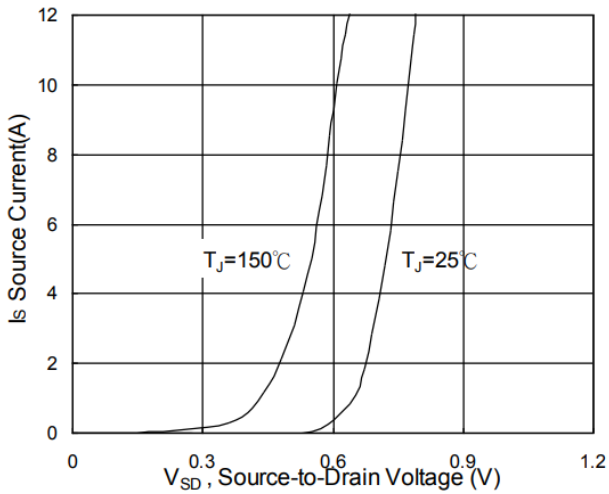
**N-CHANNEL CHARACTERISTIC CURVE**



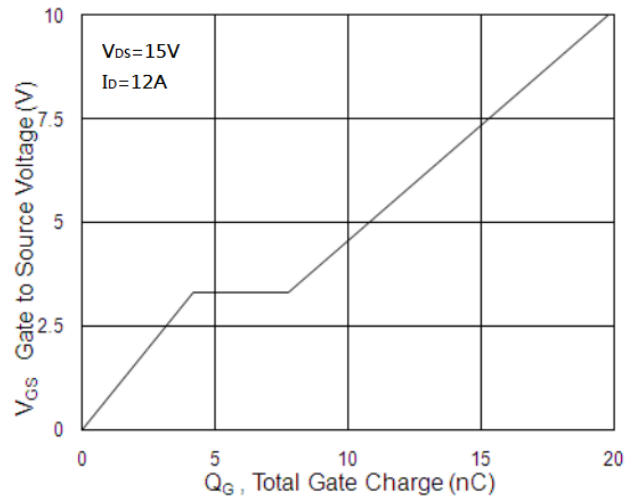
**Fig.1 Typical Output Characteristics**



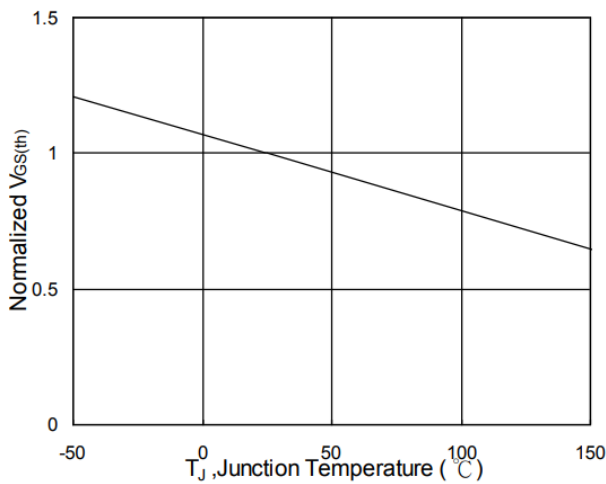
**Fig.2 On-Resistance vs. G-S Voltage**



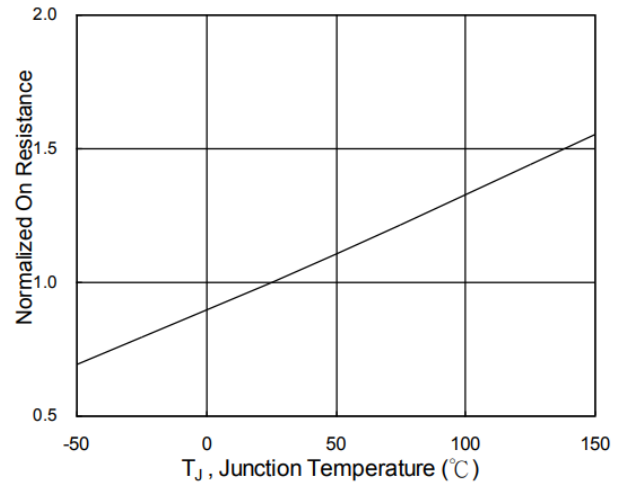
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-Charge Characteristics**

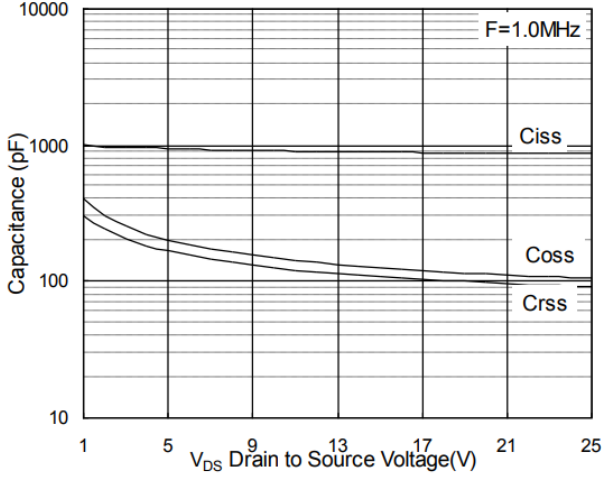


**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**

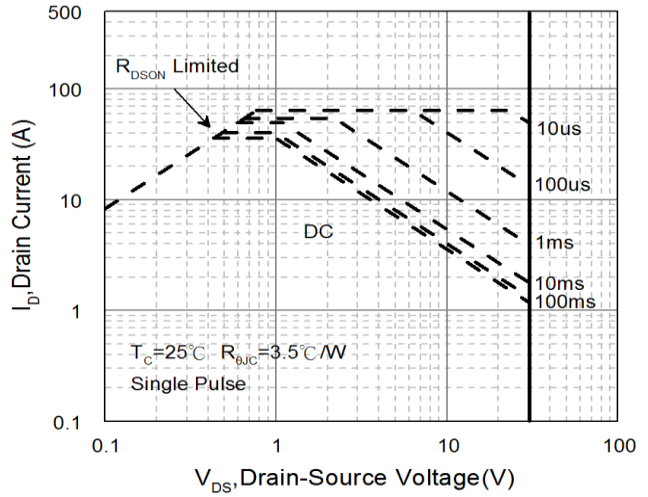


**Fig.6 Normalized  $R_{DS(ON)}$  vs.  $T_J$**

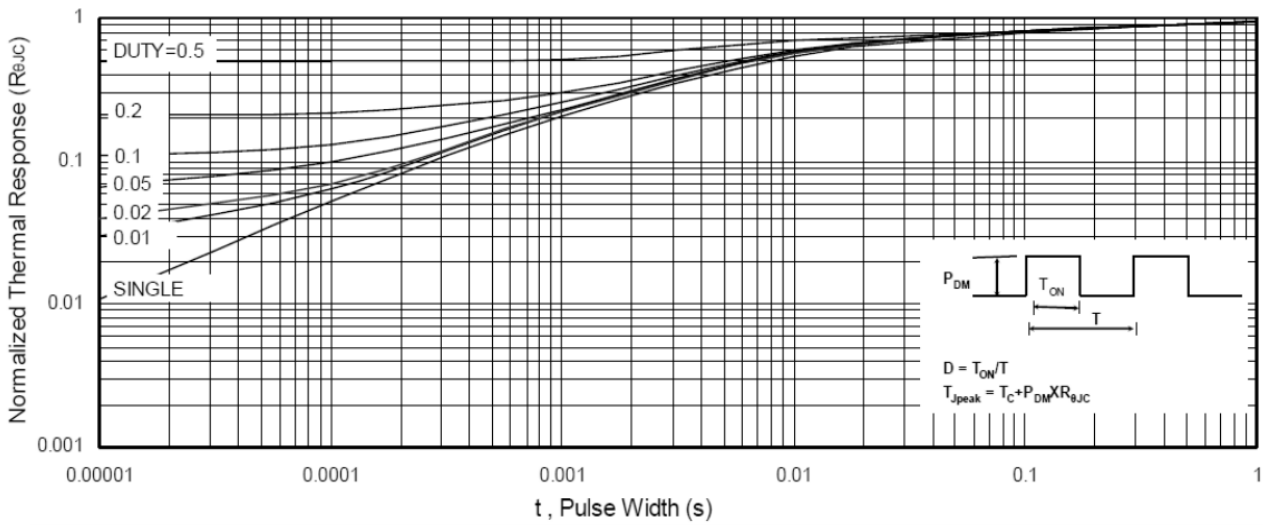
**N-CHANNEL CHARACTERISTIC CURVE**



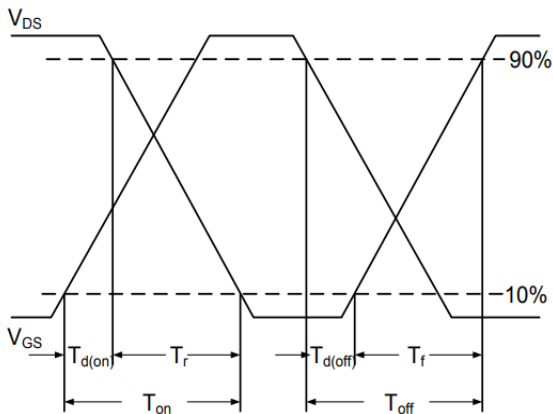
**Fig.7 Capacitance**



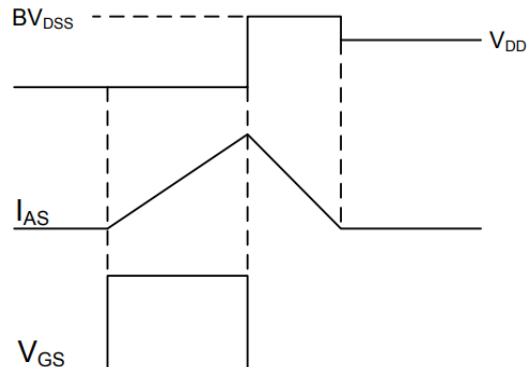
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

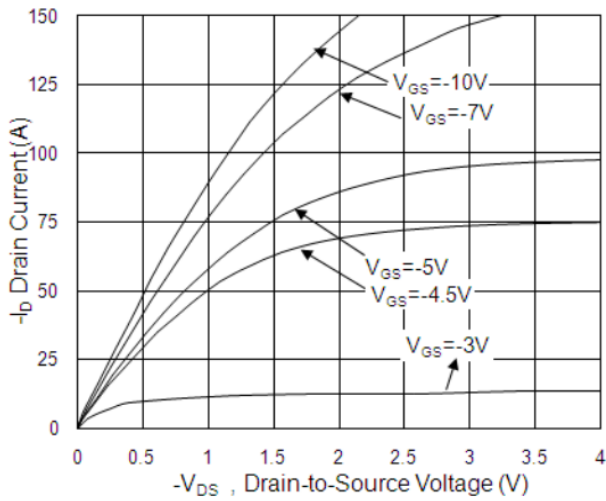


**Fig.10 Switching Time Waveform**

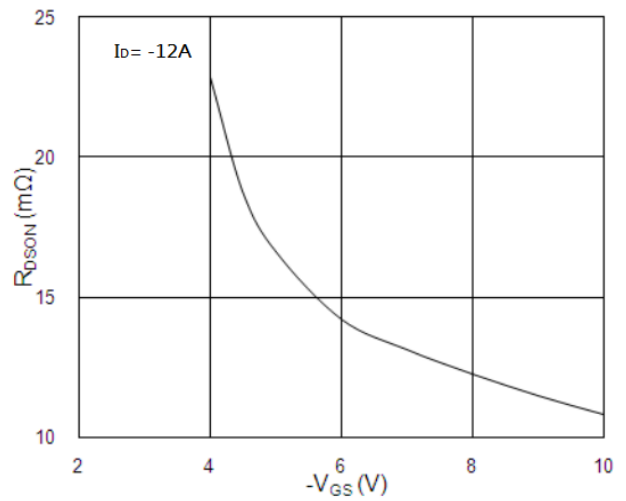


**Fig.11 Unclamped Inductive Switching Waveform**

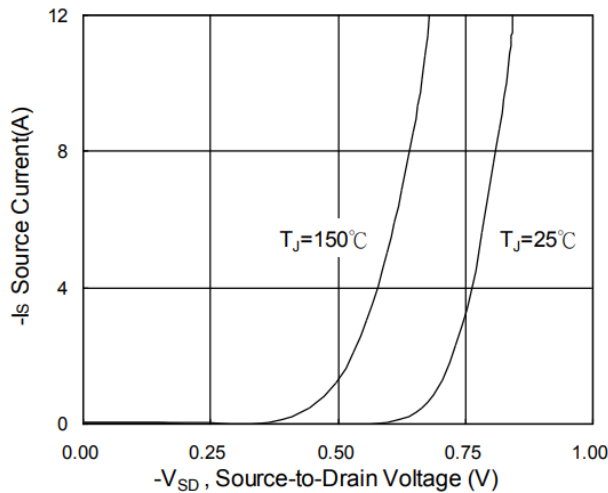
**P-CHANNEL CHARACTERISTIC CURVE**



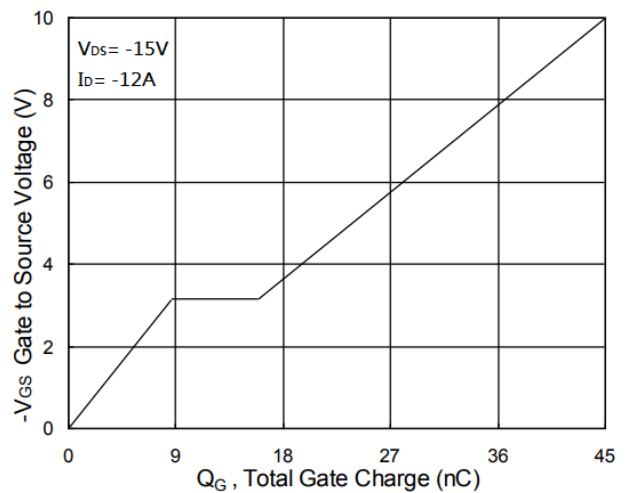
**Fig.1 Typical Output Characteristics**



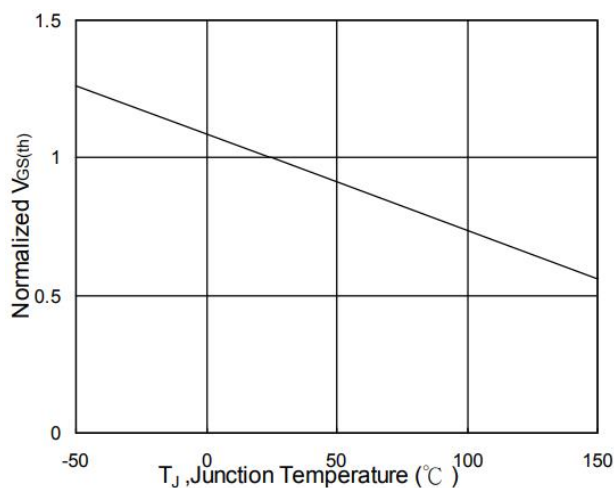
**Fig.2 On-Resistance vs. G-S Voltage**



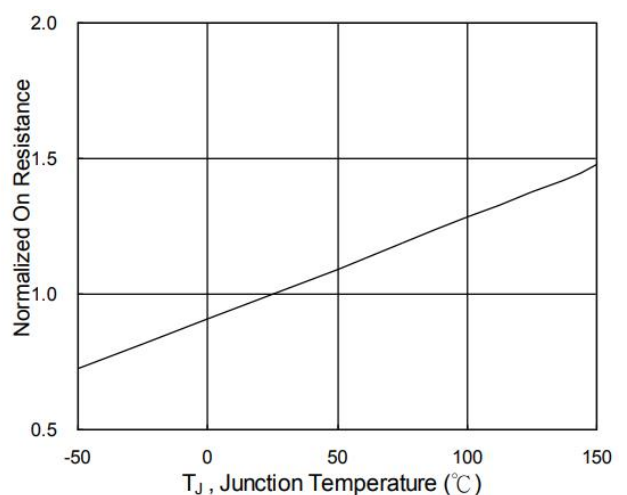
**Fig.3 Forward Characteristics of Reverse**



**Fig.4 Gate-charge Characteristics**

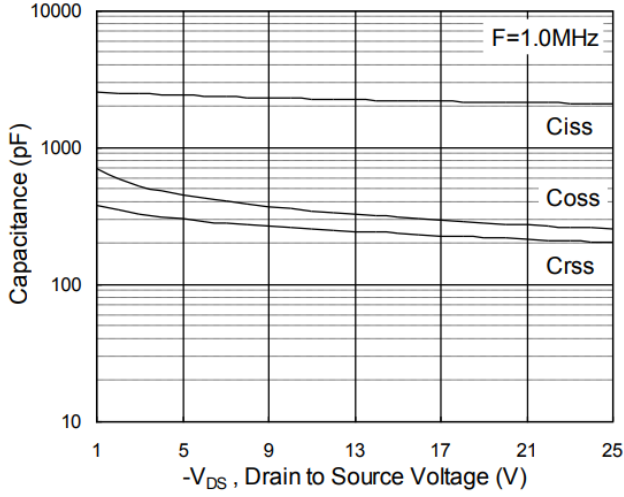


**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**

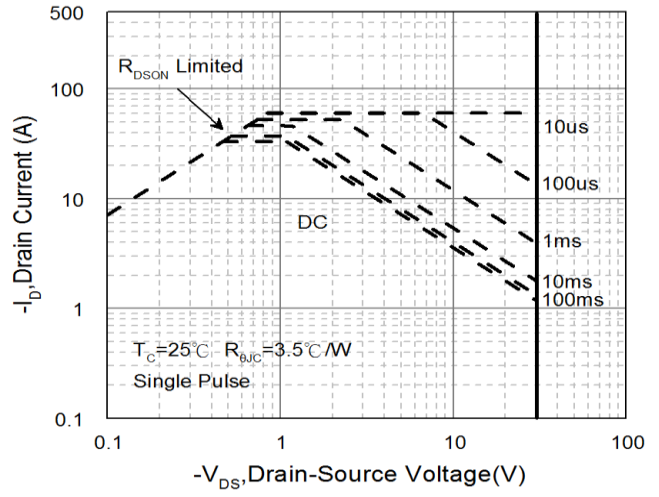


**Fig.6 Normalized  $R_{DS(ON)}$  vs.  $T_J$**

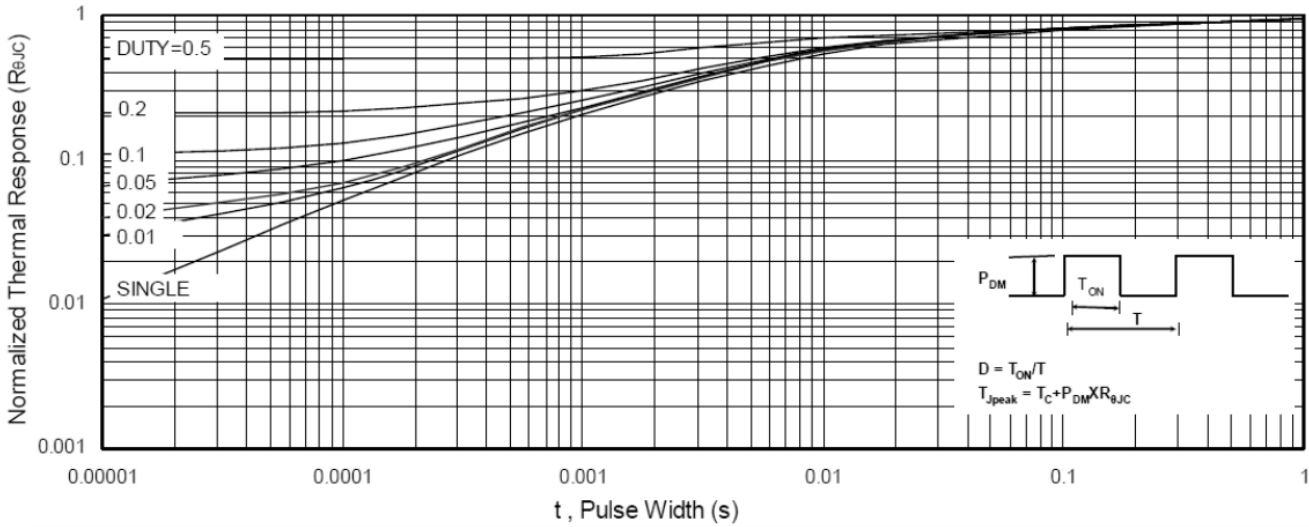
**P-CHANNEL CHARACTERISTIC CURVE**



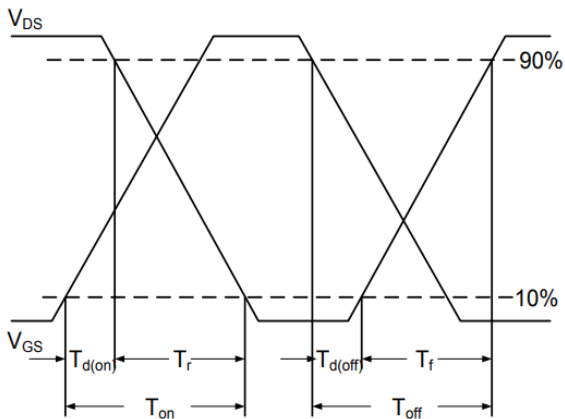
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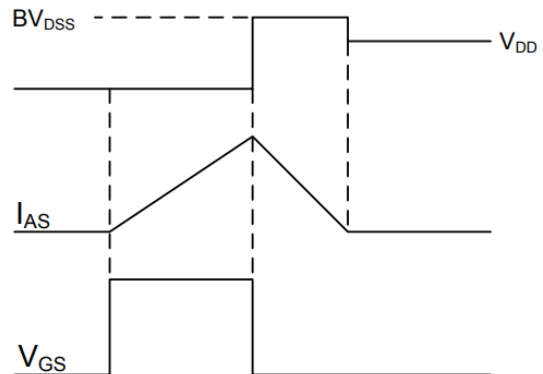
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**



**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Switching Waveform**